

Search Notes

Application/Control No.

10/706,902

Examiner

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Applicant(s)/Patent under
Reexamination

CHAE ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	66	3/23/2007	BT
216	67	3/23/2007	BT
216	71	3/23/2007	BT
216	72	3/23/2007	BT
216	74	3/23/2007	BT
438	725	3/23/2007	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
216	66	3/23/2007	BT
216	67	3/23/2007	BT
216	71	3/23/2007	BT
216/72 216/74 438/725		3/23/2007	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT, IBM_TDB databases	3/23/2007	BT